Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination TOGAWA ET AL. Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,643,061 A	07-1997	Jackson et al.	451/289
*	В	US-5,857,899 A	01-1999	Volodarsky et al.	451/72
*	C	US-6,241,591 B1	06-2001	Jackson et al.	451/287
*	۵	US-2002/0042246 A1	04-2002	Togawa et al.	451/288
*	Ш	US-2002/0081950 A1	06-2002	Sharan, Sujit	451/53
*	F	US-2002/0132559 A1	09-2002	Togawa, Tetsuji	451/8
*	G	US-2002/0187728 A1	12-2002	Kiuchi et al.	451/5
*	Η	US-6,648,734 B2	11-2003	Chin et al.	451/41
*	-	US-2005/0126708 A1	06-2005	Chen et al.	156/345.14
	7	US-			
	K	US-			
	٦	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	е	Classification
	N	JP 2000228377 A	08-2000	Japan	HAMANAKA, MAS	ASHI	H01L 21/304
	0						
	Р						
	Q						
	R						
	s						
	T						

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.